

**Search Notes**

Application/Control No.

10/021,719

Examiner

DUNG A. LE

Applicant(s)/Patent under  
Reexamination

TANAKA, KOICHIRO

Art Unit

2818

**SEARCHED**

Class	Subclass	Date	Examiner
438	166	3/18/2005	DLE
	487		
	308		
	378		
	795		
219	121.65		
	121.76		

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
IEEE,PGPUB,JPO,EPO,EAST, IMB	3/18/2005	DLE
438/166,306,378,795 Interference search	10/28/2005	DLE

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner